Examiner-Initiated Interview Summ		Application No.	Ap	plicant(s)	
	nmary	10/603,983	HA	ASEGAWA ET	AL.
		Examiner	Ar	t Unit	
		Kevin M Bernatz	17	73	
All Participants:		Status of Application	on:		
(1) Kevin M Bernatz.		(3)			
(2) <u>Gustavo Siller</u> .		(4)	•		
Date of Interview: 24 June 2005		Time: <u>AM</u>			
	☐ Applica	ant's representative)			
Part I.					
Rejection(s) discussed: all					
Claims discussed: 1,30					
Prior art documents discussed: N/A					
Part II.					
SUBSTANCE OF INTERVIEW DESCRIBING TO See Continuation Sheet	HE GENE	RAL NATURE OF WHA	T WAS DIS	SCUSSED:	
Part III.	•				
<ul> <li>It is not necessary for applicant to provide a solution of the interview in the Notice of Allowability.</li> <li>It is not necessary for applicant to provide a solution of all issues. A brief</li> </ul>	cation. The separate i	e examiner will provide record of the substance	a written so	ummary of the	ne substance
U: m ps					
(Examiner/SPE Signature)	(Applicant	/Applicant's Representa	tive Signat	ure – if appr	opriate)

Continuation of Substance of Interview including description of the general nature of what was discussed: The Examiner indicated that positively reciting that the present sensor was a current-in-plane (CiP) type sensor wherein the electrode layers are in contact with the side portions of the multilayer film along the track width direction would distinguish over the prior art CPP structures wherein the electrodes are offset from the multilayer film in the track width direction. The Examiner further noted that the positive recitation of "current-in-plane" insured that the scope afforded to the term "electrode layers" must function to provide a current in the plane of the films and would not be read on by non-magnetic underlayers, etc. which happened to be formed of materials typically used as conductive electrodes/leads in MR sensors.